





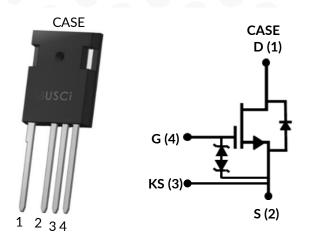








UF3C065040K4S



Part Number	Package	Marking
UF3C065040K4S	TO-247-4L	UF3C065040K4S









650V-42m Ω SiC Cascode

Rev. A, January 2019

Description

United Silicon Carbide's cascode products co-package its high-performance F3 SiC fast JFETs with a cascode optimized MOSFET to produce the only standard gate drive SiC device in the market today. This series exhibits very fast switching using a 4-terminal TO-247-package and the best reverse recovery characteristics of any device of similar ratings. These devices are excellent for switching inductive loads, and any application requiring standard gate drive.

Features

- Typical on-resistance R_{DS(on),typ} of 42mΩ
- Maximum operating temperature of 175°C
- Excellent reverse recovery
- Low gate charge
- Low intrinsic capacitance
- ESD protected, HBM class 2
- TO-247-4L package for faster switching, clean gate waveforms

Typical applications

- EV charging
- PV inverters
- Switch mode power supplies
- Power factor correction modules
- Motor drives
- Induction heating













Maximum Ratings

Parameter	Symbol	Test Conditions	Value	Units
Drain-source voltage	V_{DS}		650	V
Gate-source voltage	V_{GS}	DC	-25 to +25	V
Continuous drain current ¹	I _D	T _C = 25°C	54	Α
Continuous drain current		T _C = 100°C	40	Α
Pulsed drain current ²	I _{DM}	T _C = 25°C	125	А
Single pulsed avalanche energy ³	E _{AS}	L=15mH, I _{AS} =3.19A	76	mJ
Power dissipation	P _{tot}	T _C = 25°C	326	W
Maximum junction temperature	$T_{J,max}$		175	°C
Operating and storage temperature	T_J, T_{STG}		-55 to 175	°C
Max. lead temperature for soldering, 1/8" from case for 5 seconds	T _L		250	°C

- 1. Limited by $T_{J,\text{max}}$
- 2. Pulse width $t_{\rm p}$ limited by $T_{\rm J,max}$
- 3. Starting $T_J = 25^{\circ}C$

Thermal Characteristics

Parameter	Symbol	Test Conditions	Value			Units
			Min	Тур	Max	Offics
Thermal resistance, junction-to-case	$R_{ heta$ JC			0.35	0.46	°C/W













Electrical Characteristics (T_J = +25°C unless otherwise specified)

Typical Performance - Static

Parameter	Symbol	Test Conditions		Unita		
			Min	Тур	Max	- Units
Drain-source breakdown voltage	BV _{DS}	V_{GS} =0V, I_D =1mA	650			V
Total drain leakage current	I _{DSS}	V _{DS} =650V, V _{GS} =0V, T _J =25°C		0.7	150	- μΑ
		V _{DS} =650V, V _{GS} =0V, T _J =175°C		10		
Total gate leakage current	I _{GSS}	V _{DS} =0V, T _J =25°C, V _{GS} =-20V / +20V		6	±20	μΑ
Drain-source on-resistance	R _{DS(on)}	V _{GS} =12V, I _D =40A, T _J =25°C		42	52	mΩ
		V _{GS} =12V, I _D =40A, T _J =175°C		78		11122
Gate threshold voltage	$V_{G(th)}$	V_{DS} =5V, I_D =10mA	4	5	6	V
Gate resistance	R_G	f=1MHz, open drain		4.5		Ω

Typical Performance - Reverse Diode

Parameter	Symbol	Test Conditions		11.2		
			Min	Тур	Max	Units
Diode continuous forward current ¹	I _S	T _C =25°C			54	Α
Diode pulse current ²	I _{S,pulse}	T _C =25°C			125	А
Forward voltage	V _{FSD}	V _{GS} =0V, I _F =20A, T _J =25°C		1.5	1.75	٧
		V _{GS} =0V, I _F =20A, T _J =175°C		1.8		
Reverse recovery charge	Q _{rr}	V_R =400V, I_F =40A, V_{GS} =-5V, R_{G_EXT} =20 Ω		138		nC
Reverse recovery time	t _{rr}	di/dt=1100A/μs, T _J =25°C		38		ns
Reverse recovery charge	Q _{rr}	V_R =400V, I_F =40A, V_{GS} =-5V, R_{G_EXT} =20 Ω		137		nC
Reverse recovery time	t _{rr}	di/dt=1100A/μs, Τ _J =150°C		38		ns













Typical Performance - Dynamic

Parameter	Symbol	Test Conditions	Value			Units
Parameter			Min	Тур	Max	Units
Input capacitance	C_{iss}	- V _{DS} =100V, V _{GS} =0V - f=100kHz		1500		
Output capacitance	C_{oss}			200		pF
Reverse transfer capacitance	C_{rss}	1-100KHZ		2.2		
Effective output capacitance, energy related	$C_{oss(er)}$	V_{DS} =0V to 400V, V_{GS} =0V		146		pF
Effective output capacitance, time related	$C_{oss(tr)}$	V_{DS} =0V to 400V, V_{GS} =0V		325		pF
C _{OSS} stored energy	E_{oss}	V _{DS} =400V, V _{GS} =0V		11.7		μЈ
Total gate charge	Q_{G}	V _{DS} =400V, I _D =40A,		43		
Gate-drain charge	Q_{GD}	$V_{DS} = -5V \text{ to } 12V$		11		nC
Gate-source charge	Q_{GS}	VGS - 3V to 12V		19		
Turn-on delay time	$t_{d(on)}$	$V_{DS}=400V,\ I_{D}=40A,$ Gate Driver =-5V to +12V, Turn-on $R_{G,EXT}=8.5\Omega,$ Turn-off $R_{G,EXT}=20\Omega$ Inductive Load, FWD: same device with $V_{GS}=-5V,\ R_{G}=10\Omega,$ $T_{J}=25^{\circ}C$		26		- ns
Rise time	t _r			24		
Turn-off delay time	$t_{d(off)}$			45		
Fall time	t _f			10		
Turn-on energy	E _{ON}			227		
Turn-off energy	E _{OFF}			82		μЈ
Total switching energy	E_TOTAL			309		
Turn-on delay time	$t_{d(on)}$	V_{DS} =400V, I_{D} =40A,		22		
Rise time	t_r	$\label{eq:Gate Driver} Gate Driver =-5V to \\ +12V, \\ Turn-on R_{G,EXT}=8.5\Omega, \\ Turn-off R_{G,EXT}=20\Omega \\ Inductive Load, \\ FWD: same device with \\ V_{GS}=-5V, R_{G}=10\Omega, \\ T_{J}=150^{\circ}C$		22		- ns
Turn-off delay time	$t_{d(off)}$			45		115
Fall time	t _f			8		
Turn-on energy	E _{ON}			207		
Turn-off energy	E _{OFF}			64		μJ
Total switching energy	E _{TOTAL}			271		













Typical Performance Diagrams

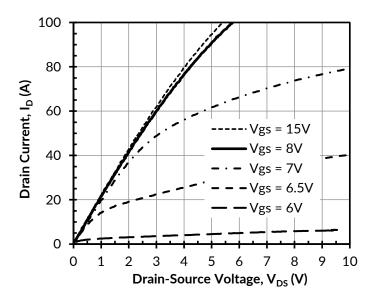


Figure 1. Typical output characteristics at T_J = -55°C, tp < 250 μ s

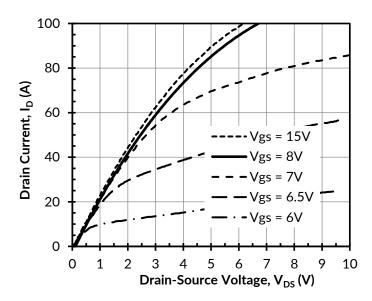


Figure 2. Typical output characteristics at $T_J = 25$ °C, tp < 250μ s

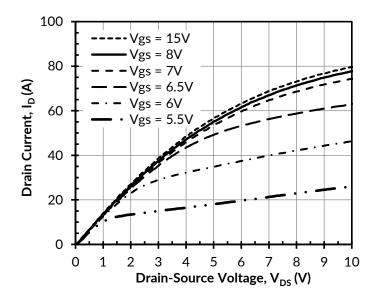


Figure 3. Typical output characteristics at T_J = 175°C, tp < 250 μ s

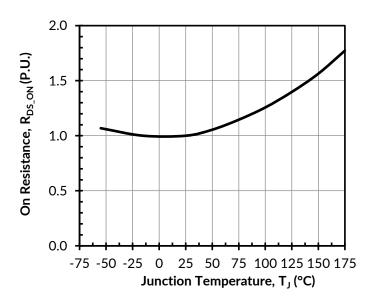


Figure 4. Normalized on-resistance vs. temperature at V_{GS} = 12V and I_{D} = 40A



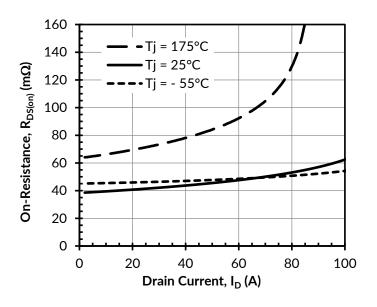












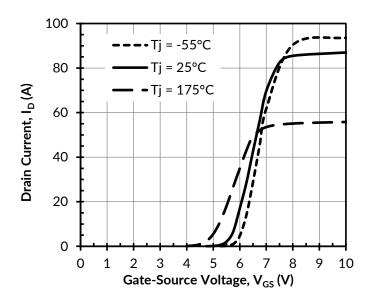
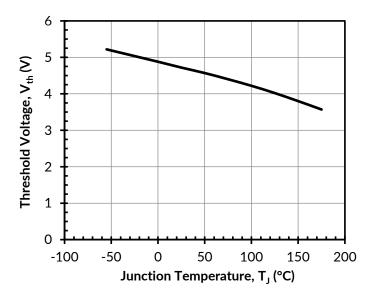


Figure 5. Typical drain-source on-resistances at V_{GS} = 12V

Figure 6. Typical transfer characteristics at $V_{DS} = 5V$



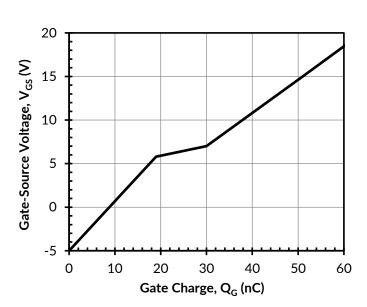


Figure 7. Threshold voltage vs. junction temperature at V_{DS} = 5V and I_{D} = 10mA

Figure 8. Typical gate charge at V_{DS} = 400V and I_{D} = 40A





0









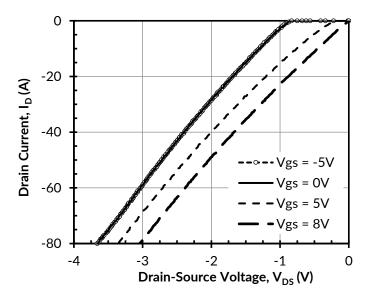
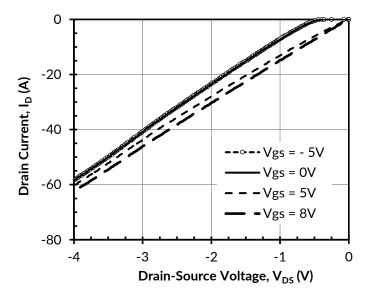


Figure 9. 3rd quadrant characteristics at $T_J = -55$ °C

Figure 10. 3rd quadrant characteristics at $T_J = 25$ °C



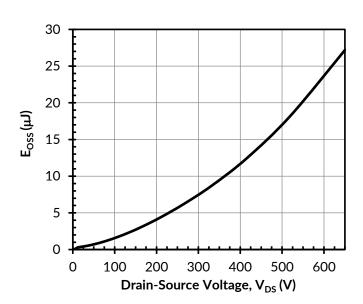


Figure 11. 3rd quadrant characteristics at $T_J = 175$ °C

Figure 12. Typical stored energy in C_{OSS} at $V_{GS} = 0V$













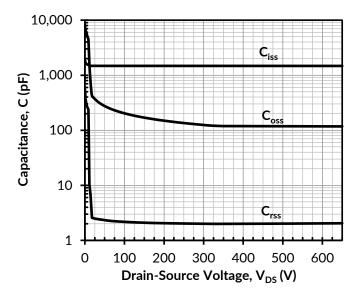


Figure 13. Typical capacitances at f = 100kHz and $V_{GS} = 0V$

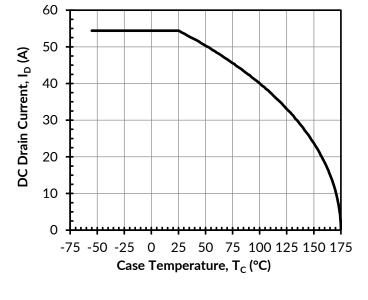


Figure 14. DC drain current derating

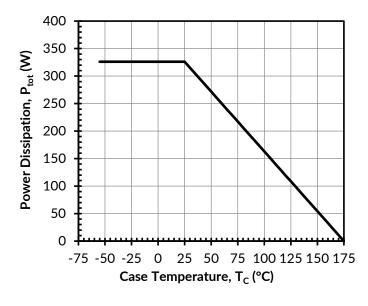


Figure 15. Total power dissipation

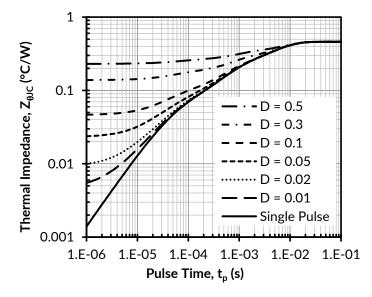


Figure 16. Maximum transient thermal impedance













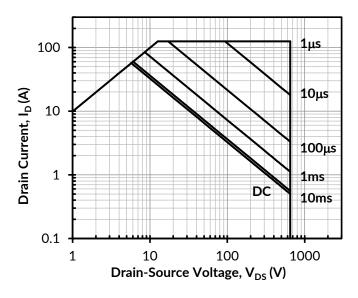


Figure 17. Safe operation area at T_C = 25°C, D = 0, Parameter t_p

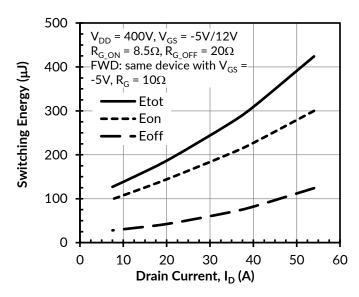


Figure 18. Clamped inductive switching energy vs. drain current at $T_J = 25$ °C

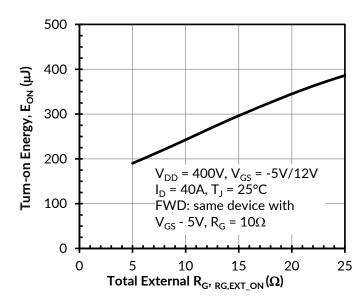


Figure 19. Clamped inductive switching turn-on energy vs. $R_{\text{G,EXT_ON}}$

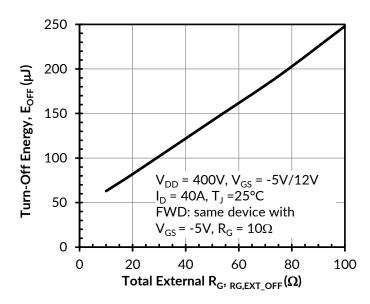


Figure 20. Clamped inductive switching turn-off energy vs. R_{G,EXT_OFF}



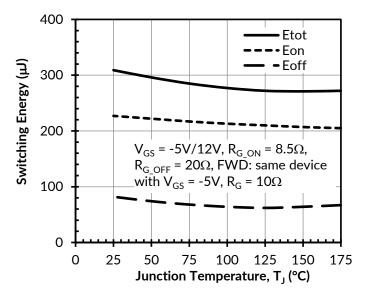












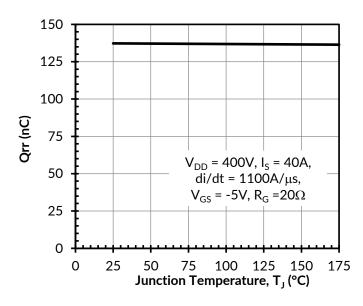


Figure 21. Clamped inductive switching energy vs. junction temperature at V_{DS} = 400V and I_{D} = 40A

Figure 22. Reverse recovery charge Qrr vs. junction temperature

Applications Information

SiC cascodes are enhancement-mode power switches formed by a high-voltage SiC depletion-mode JFET and a low-voltage silicon MOSFET connected in series. The silicon MOSFET serves as the control unit while the SiC JFET provides high voltage blocking in the off state. This combination of devices in a single package provides compatibility with standard gate drivers and offers superior performance in terms of low on-resistance ($R_{DS(on)}$), output capacitance (C_{oss}), gate charge (Q_G), and reverse recovery charge (Q_{rr}) leading to low conduction and switching losses. The SiC cascodes also provide excellent reverse conduction capability eliminating the need for an external anti-parallel diode.

Like other high performance power switches, proper PCB layout design to minimize circuit parasitics is strongly recommended due to the high dv/dt and di/dt rates. An external gate resistor is recommended when the cascode is working in the diode mode in order to achieve the optimum reverse recovery performance. For more information on cascode operation, see www.unitedsic.com.

Disclaimer

United Silicon Carbide, Inc. reserves the right to change or modify any of the products and their inherent physical and technical specifications without prior notice. United Silicon Carbide, Inc. assumes no responsibility or liability for any errors or inaccuracies within.

Information on all products and contained herein is intended for description only. No license, express or implied, to any intellectual property rights is granted within this document.

United Silicon Carbide, Inc. assumes no liability whatsoever relating to the choice, selection or use of the United Silicon Carbide, Inc. products and services described herein.